

USB 3.0 Product Test Matrix

		USB 3.0 xHCI /SuperSpeed Testing									USB 2.0 LS/FS/HS Testing			
		USBCV Chap 9 Tests	USBCV Device Specific Tests	xHCI Host Tests	3.0 Electrical	3.0 Interop	3.0 Backwards Compatibility	Link Testing	xHCI HSET	Current Test Measurement	USBCV Chap 9	USBCV Device Specific Tests	2.0 Gold Tree Interop using EHCI	2.0 Electrical
xHCI Host	Silicon	x	n/a	Full test suite	x	x	x	x	x	?	All speeds	All	n/a	x
	End Product	x	n/a	Subset	x	x	x	x	x	?	All speeds	All	n/a	x
USB 3.0 Devices Silicon/IP/End Product	Device	x	n/a	n/a	x	x	x	x	x	x	Run for all 2.0 supported speeds	n/a	x	x
	Hub	x	Hub tests	n/a	On both upstream and downstream ports	x	x	x	x	x	Run for all 2.0 supported speeds	Hub Tests	x	x
	MSD Device	x	MSD tests	n/a	x	x	x	x	x	x	Run for all 2.0 supported speeds	MSD Tests	x	x

Test Notes:	Subset of xHCI tests: register interface tests, port speed and port tests, 1 Isoch, bulk, control interrupt loopback on 1 port
	Until we have a 3.0 certified hub, substitute various 3.0 devices being swapped in and out for 3.0 interop
	3.0 Electricals on Agilent, LeCroy and Tek using external BERT
	xHCI Host USB 3.0 CV chap 9 for these devices: 2.0 hub, 3.0 hub, SS/HS/FS/LS devices